

November 2013

# **FDMS037N08B**

# N-Channel PowerTrench $^{\mbox{\scriptsize R}}$ MOSFET 75 V, 100 A, 3.7 m $\Omega$

#### **Features**

- $R_{DS(on)}$  = 3.01  $m\Omega$  (Typ.) @  $V_{GS}$  = 10 V,  $I_D$  = 50 A
- Low FOM R<sub>DS(on)</sub>\*Q<sub>G</sub>
- Low Reverse Recovery Charge, Q<sub>rr</sub> = 80 nC
- · Soft Reverse Recovery Body Diode
- · Enables Highly Efficiency in Synchronous Rectification
- · Fast Switching Speed
- · 100% UIL Tested
- · RoHS Compliant

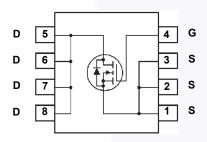
# **Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advance PowerTrench® process that has been tailored to minimize the on-state resistance while maintaining superior switching performance.

#### **Applications**

- Synchronous Rectification for ATX / Server / Telecom PSU
- · Battery Protection circuit
- · DC Motor Drives and Uninterruptible Power Supplies





### MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted.

Symbol		Parameter		FDMS037N08B	Unit	
V <sub>DSS</sub>	Drain to Source Voltage			75	V	
V <sub>GSS</sub>	Gate to Source Voltage			±20	V	
		- Continuous (T <sub>C</sub> = 25°C)		100		
I <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 25°C, Silicon Limited)		128	Α	
		- Continuous (T <sub>A</sub> = 25°C)	(Note 1a)	19.9		
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 2)	400	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 3)	180.6	mJ	
D	Power Discipation	(T <sub>C</sub> = 25°C)		104.2	W	
$P_{D}$	Power Dissipation	$(T_A = 25^{\circ}C)$	(Note 1a)	0.83	W	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperatu	ire Range		-55 to +150	°C	

#### **Thermal Characteristics**

Symbol	Parameter	FDMS037N08B	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	1.2	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max. (Note 1a)	50	- 0/00

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS037N08B	FDMS037N08B	Power 56	13 "	12 mm	3000 units

## Electrical Characteristics T<sub>J</sub>= 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	75	-	-	V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C	-	39	-	mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 60 V, V <sub>GS</sub> = 0 V	-	-	1	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

#### On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	2.5	-	4.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 50 \text{ A}$	1	3.01	3.7	mΩ
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 50 A	ı	108	ı	S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance		-	4550	5915	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 37.5 \text{ V}, V_{GS} = 0 \text{ V}$ 	-	1060	1380	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	-	30.2	45	pF
C <sub>oss</sub> (er)	Energy Releted Output Capacitance	V <sub>DS</sub> = 37.5 V, V <sub>GS</sub> = 0 V	-	1702	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	76.8	100	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 37.5 \text{ V}, I_{D} = 50 \text{ A}$	-	27.5	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 0 V to 10 V	-	17.4	-	nC
V <sub>plateau</sub>	Gate Plateau Volatge	(Note	- 4)	5.1	-	V
Q <sub>sync</sub>	Total Gate Charge Sync.	V <sub>DS</sub> = 0 V, I <sub>D</sub> = 50 A	-	66.3	-	nC
Q <sub>oss</sub>	Output Charge	V <sub>DS</sub> = 37.5 V, V <sub>GS</sub> = 0 V	-	74.6	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	1.28	-	Ω

# **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	34.9	80	ns
t <sub>r</sub>		$V_{DD} = 37.5 \text{ V}, I_{D} = 50 \text{ A}$	-	20.1	50	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS}$ = 10 V, $R_{G}$ = 4.7 $\Omega$	-	55.3	120	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	/ -	19.4	49	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	100	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	400	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 50 A		-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 50 A	-	66.8	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	84	-	nC

<sup>1.</sup>R<sub>0,IA</sub> is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,IC</sub> is guaranteed by design while R<sub>0,CA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Repetitive rating: pulse-width limited by maximum junction temperature.
- 3. L = 0.3 mH,  $I_{AS}$  = 34.7 A, starting  $T_J$  = 25°C.
- 4. Essentially independent of operating temperature typical characteristics.

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

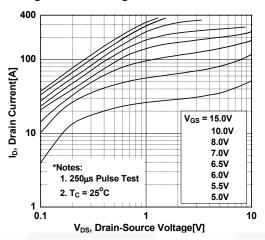
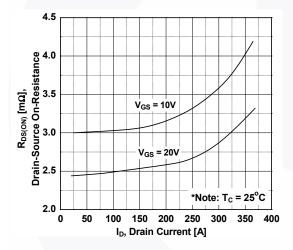


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage



**Figure 5. Capacitance Characteristics** 

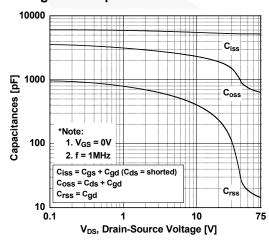


Figure 2. Transfer Characteristics

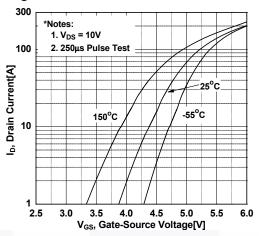
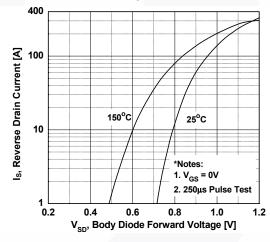
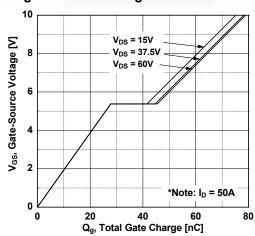


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature



**Figure 6. Gate Charge Characteristics** 



# **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

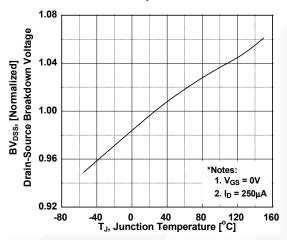


Figure 9. Maximum Safe Operating Area

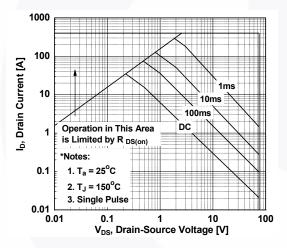


Figure 11. Eoss vs. Drain to Source Voltage

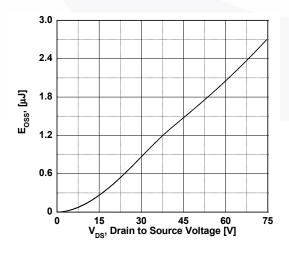


Figure 8. On-Resistance Variation vs. Temperature

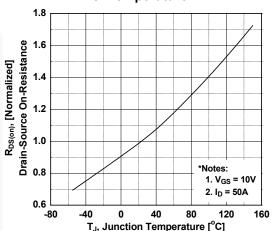


Figure 10. Maximum Drain Current vs. Case Temperature

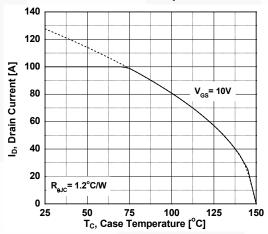
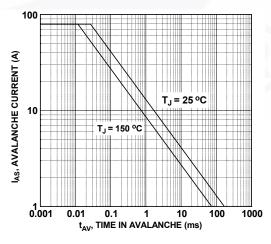
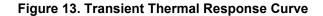


Figure 12. Unclamped Inductive Switching Capability



# **Typical Performance Characteristics** (Continued)



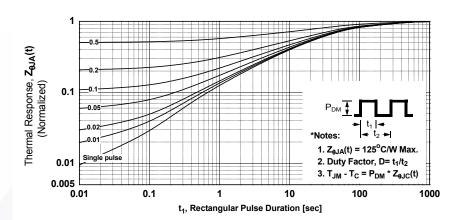


Figure 14. Gate Charge Test Circuit & Waveform

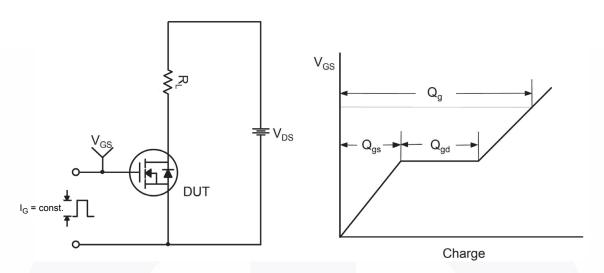


Figure 15. Resistive Switching Test Circuit & Waveforms

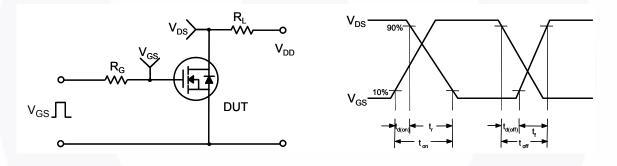
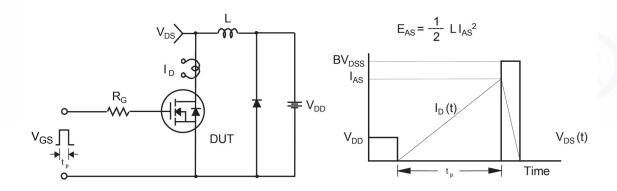


Figure 16. Unclamped Inductive Switching Test Circuit & Waveforms



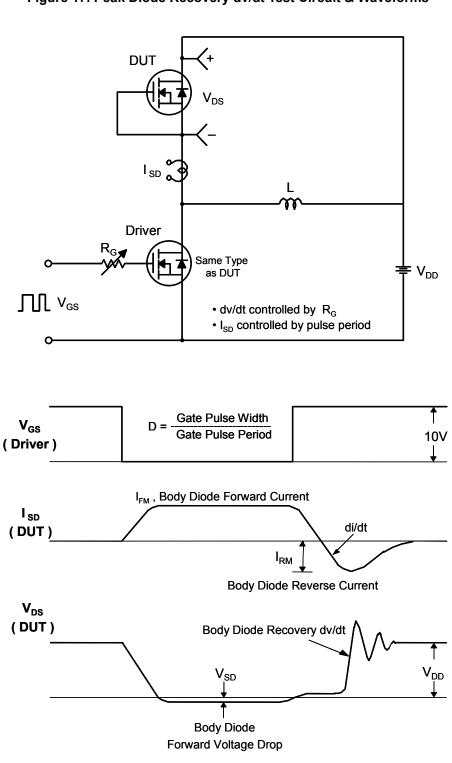
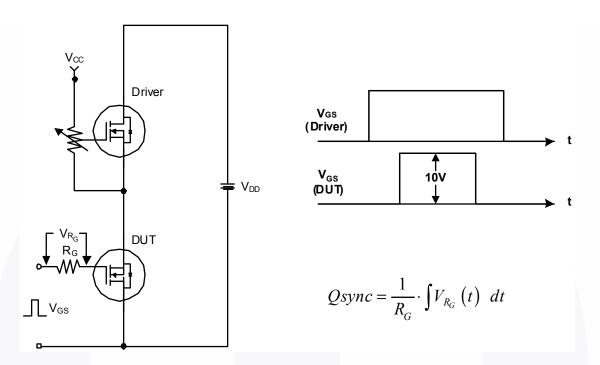


Figure 17. Peak Diode Recovery dv/dt Test Circuit & Waveforms

Figure 18. Total Gate Charge Qsync. Test Circuit & Waveforms





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